Docket Number (Optional) Application Number INFORMATION DISCLOSURE CITATION (Z) 99023 P 09/760066 Applicant(s) (Use several sheets if necessary) Schuster Filing Date Group Art Unit 1-12-01 llioz8% U.S. PATENT DOCUMENTS EXAMINER OD -DOCUMENT NUMBER DATE NAME CLASS SUBCLASS FILING DATE 5,396,367 03/07/1995 IF APPROPRIATE Ono et al. 602B5,469,299 11/21/1995 Nagano 5,805,344 09/08/1998 Sasaya et al. 5,099,361 03/24/1992 Yamamoto et al. FOREIGN PATENT DOCUMENTS REF DOCUMENT NUMBER DATE COUNTRY CLASS Translation SUBCLASS EP 0 783 137 A2 YES 09/11/1996 European G03F 7/20 DE 196 53 983 A1 21/12/96 Germany GQ2B 3/24 EP 0 857 985 A1 14/01/98 European G028 DE 198 18 444 A1 24/04/98 Germany G02B DE-198-55-158-A Germany OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) U.S. Patent Application 09/416,105, Filed 12/10/99, Title: Microlithographic Reduction Objective, Projection Exposure Equipment and Process, 36 pgs. U.S. Patent Application 09/444,063, Filed: 19/11/99, Title: Projection Objective, 36 pgs. French Document No. 75 31231, Date: \frac{13}{10}\frac{1975}{1975}; Class: G02B 15/14; 9 pgs. Patent Abtracts of Japan; Pub. No. 11097347; Pub. Date. 09/04/99; Applicant: Nikon Corp.;37 pgs. PCT document WO 08/70407, PCT/EP99/10233, Date: 21/12/1999, Schuster; Title: Projection Lens for Microlithography EXAMINER DATE CONSIDERED 11-22-02 EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not

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